

June 2000

FQP1P50

500V P-Channel MOSFET

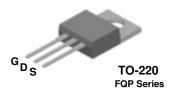
General Description

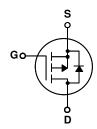
These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for electronic lamp ballast based on complementary half bridge.

Features

- -1.5A, -500V, R_{DS(on)} = 10.5 Ω @V_{GS} = -10 V Low gate charge (typical 11 nC)
- Low Crss (typical 6.0 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQP1P50	Units	
V _{DSS}	Drain-Source Voltage		-500	V	
I _D	Drain Current - Continuous (T _C = 25°C)		-1.5	Α	
	- Continuous (T _C = 100°C)		-0.95	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	-6.0	А	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	110	mJ	
I _{AR}	Avalanche Current	(Note 1)	-1.5	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	6.3	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-4.5	V/ns	
P_D	Power Dissipation (T _C = 25°C)		63	W	
	- Derate above 25°C		0.51	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.98	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-500			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -500 V, V _{GS} = 0 V			-1	μА
		V _{DS} = -400 V, T _C = 125°C			-10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = -250 μA	-3.0		-5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -0.75 A		8.0	10.5	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = -50 \text{ V}, I_D = -0.75 \text{ A}$ (Note 4)		1.26		S
C _{iss}	Input Capacitance Output Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		270 40	350 50	pF pF
C _{rss}	Reverse Transfer Capacitance			6.0	8.0	pF
Switchi	ing Characteristics					
$t_{d(on)}$	Turn-On Delay Time	V _{DD} = -250 V, I _D = -1.5 A,		9.0	30	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		25	60	ns
$t_{d(off)}$	Turn-Off Delay Time			27	65	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		30	70	ns
Q_g	Total Gate Charge	$V_{DS} = -400 \text{ V}, I_{D} = -1.5 \text{ A},$		11	14	nC
Q _{gs}	Gate-Source Charge	V _{GS} = -10 V		2.0		nC
Q_{gd}	Gate-Drain Charge	(Note 4, 5)		5.6		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				-1.5	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	orward Current			-6.0	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = -1.5 A			-5.0	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = -1.5 \text{ A},$		200		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		0.7		μС

- Notes:
 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 88mH, I_{AS} = -1.5A, V_{DD} = -50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq -1.5A, didt \leq 200A/µs, V_{DD} \leq 8V_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300µs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

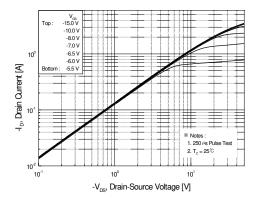


Figure 1. On-Region Characteristics

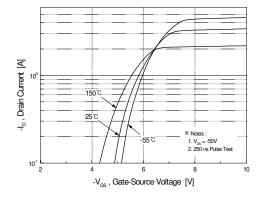


Figure 2. Transfer Characteristics

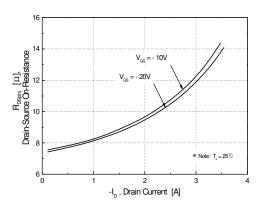


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

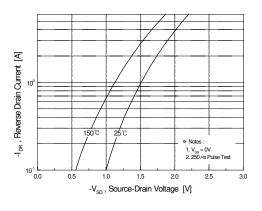


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

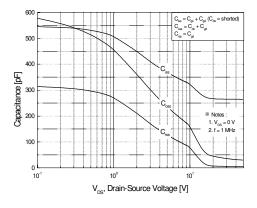


Figure 5. Capacitance Characteristics

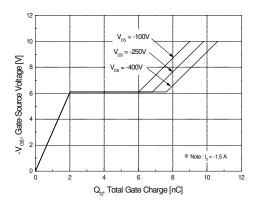
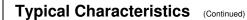
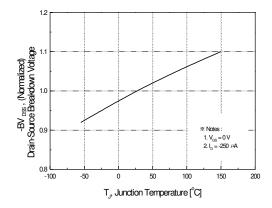


Figure 6. Gate Charge Characteristics





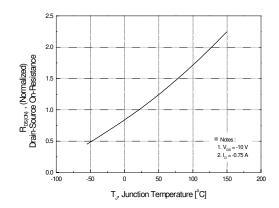
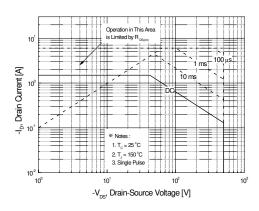


Figure 7. Breakdown Voltage Variation vs. Temperature





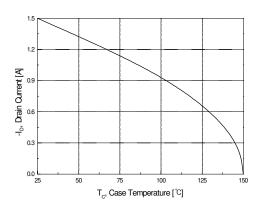


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

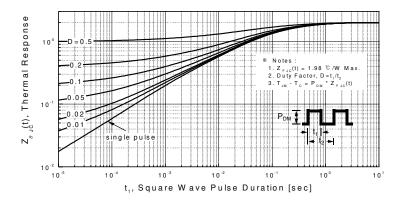
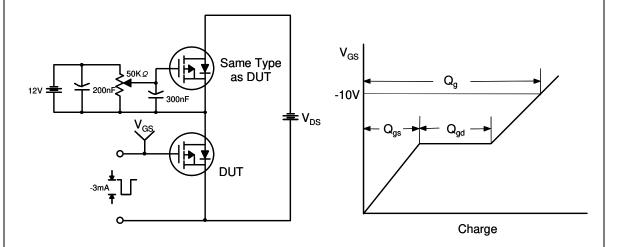


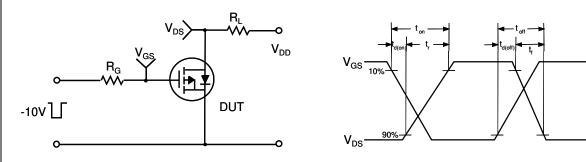
Figure 11. Transient Thermal Response Curve

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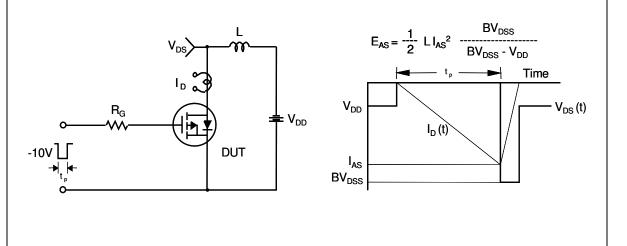
Gate Charge Test Circuit & Waveform



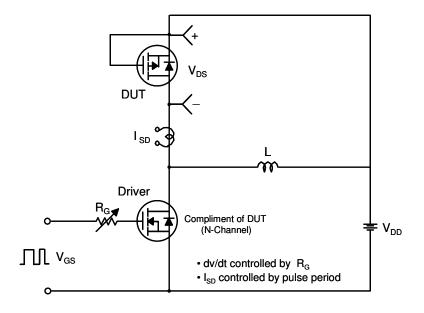
Resistive Switching Test Circuit & Waveforms

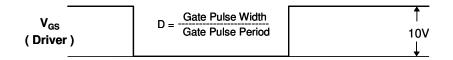


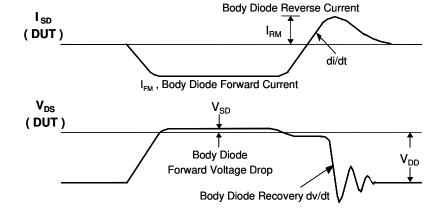
Unclamped Inductive Switching Test Circuit & Waveforms

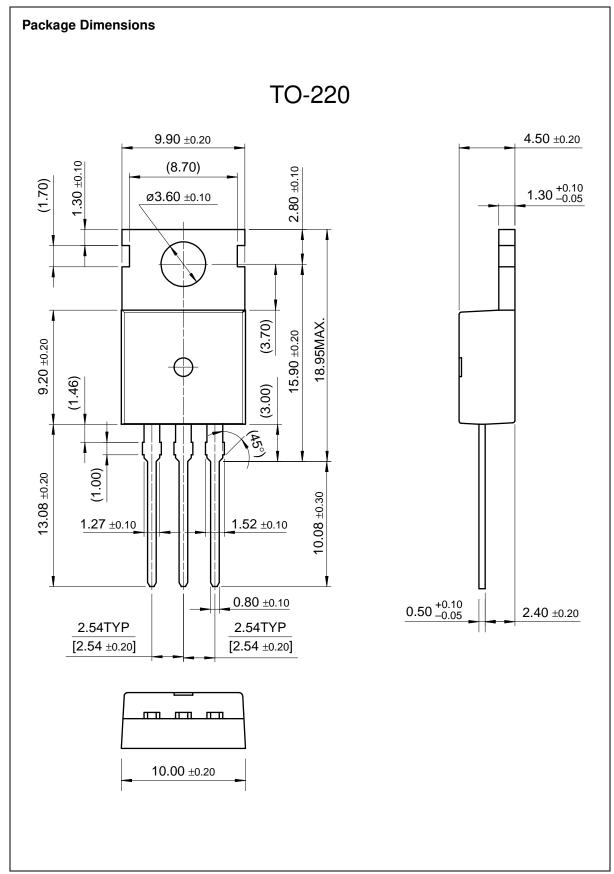


Peak Diode Recovery dv/dt Test Circuit & Waveforms









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